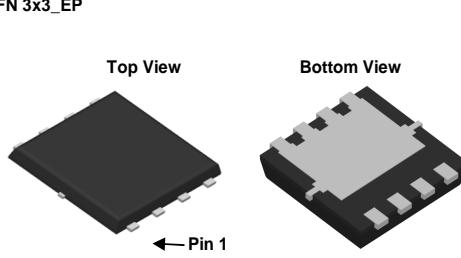
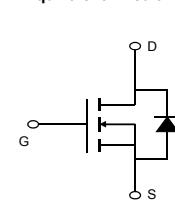


N-Channel Enhancement Mode Power MOSFET

| | |
|--|---|
| <p>Features</p> <ul style="list-style-type: none"> • 30V/30A, $R_{DS(ON)} = 10\text{m}\Omega$(Typ.)@$V_{GS}=10\text{V}$ $R_{DS(ON)} = 15\text{m}\Omega$(Typ.)@$V_{GS}=4.5\text{V}$ • Super High Dense Cell Design • Fast Switching Speed • Low gate Charge • 100% avalanche tested • Lead Free and Green Devices Available <p>Applications</p> <ul style="list-style-type: none"> • Switching Application Systems | <p>DFN 3x3_EP</p>    <p>Y :year code W :week code</p> |
|--|---|

Absolute Maximum Ratings

| Symbol | Parameter | Rating | Unit |
|--------|-----------|--------|------|
|--------|-----------|--------|------|

Common Ratings ($T_C=25^\circ\text{C}$ Unless Otherwise Noted)

| | | | |
|-----------|----------------------------------|------------------------|------------------|
| V_{DSS} | Drain-Source Voltage | 30 | V |
| V_{GSS} | Gate-Source Voltage | ± 20 | |
| T_J | Maximum Junction Temperature | 150 | $^\circ\text{C}$ |
| T_{STG} | Storage Temperature Range | -55 to 150 | $^\circ\text{C}$ |
| I_S | Diode Continuous Forward Current | $T_C=25^\circ\text{C}$ | 30 |
| | | | A |

Mounted on Large Heat Sink

| | | | | |
|--------------|--|------------------------|------|---|
| $I_{DP}^{①}$ | 300 μs Pulse Drain Current Tested | $T_C=25^\circ\text{C}$ | 120 | A |
| $I_D^{②}$ | Continuous Drain Current@ $T_C(V_{GS}=10\text{V})$ | $T_C=25^\circ\text{C}$ | 30 | A |
| | Continuous Drain Current@ $T_A(V_{GS}=10\text{V})^{③}$ | $T_A=25^\circ\text{C}$ | 10.8 | |
| P_D | Maximum Power Dissipation@ T_C | $T_C=25^\circ\text{C}$ | 29 | W |
| | Maximum Power Dissipation@ $T_A^{③}$ | $T_A=25^\circ\text{C}$ | 3.5 | |

Notes:

- ①Pulse width limited by safe operating area.
- ②Calculated continuous current based on maximum allowable junction temperature.
- ③When mounted on 1 inch square copper board, $t \leq 10\text{sec}$.
- ④Limited by T_{Jmax} , $I_{AS} = 13\text{A}$, $V_{DD} = 24\text{V}$, $R_G = 50\Omega$, Starting $T_J = 25^\circ\text{C}$.
- ⑤Pulse test; Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
- ⑥Guaranteed by design, not subject to production testing.



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PDFN 3x3 Plastic-Encapsulate MOSFETS

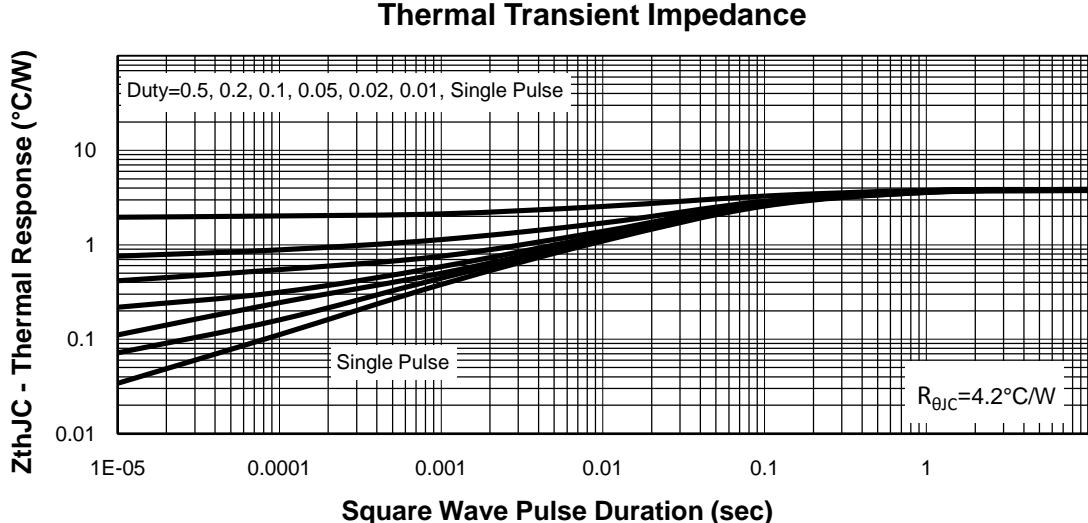
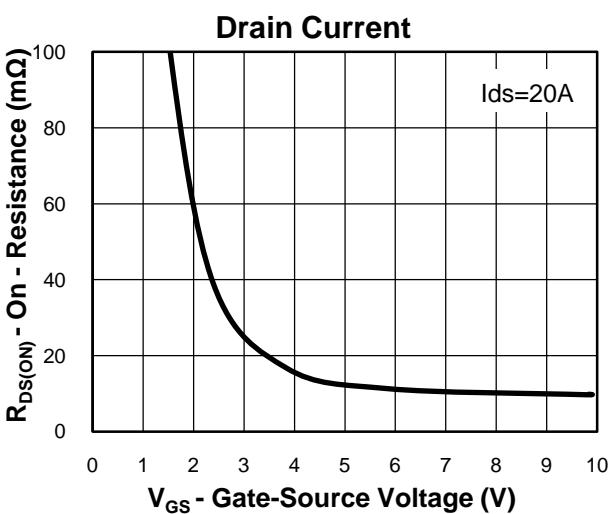
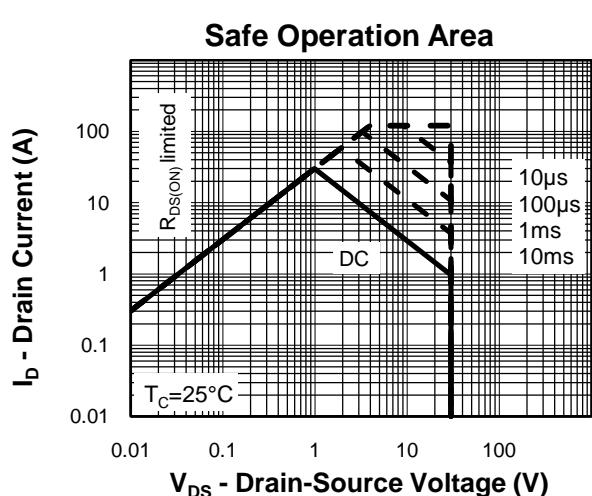
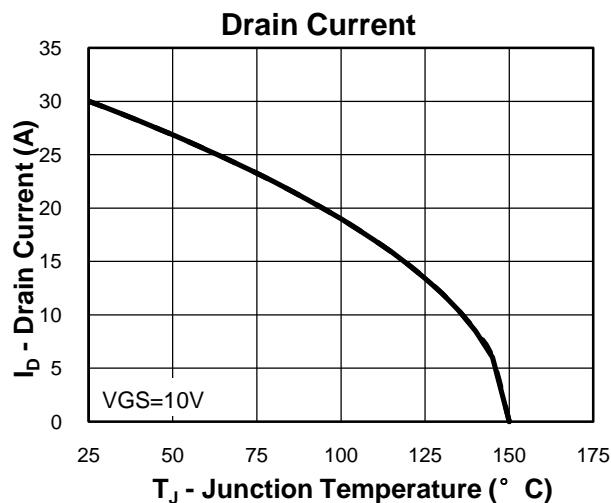
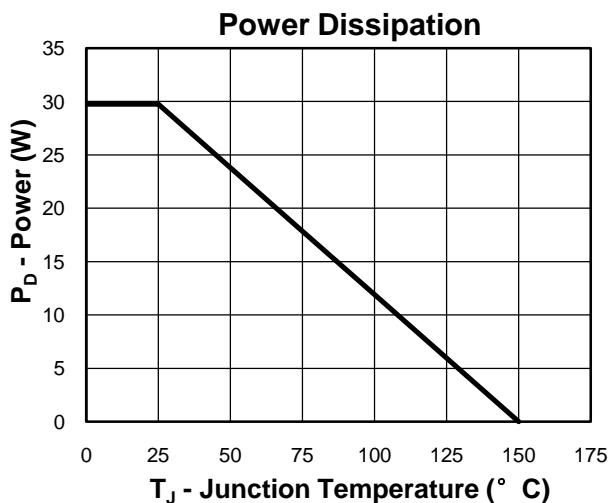
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| Symbol | Parameter | Rating | Unit |
|---------------------------------------|--|--------|------|
| R _{θJC} | Thermal Resistance-Junction to Case | 4.2 | °C/W |
| R _{θJA} ⁽³⁾ | Thermal Resistance-Junction to Ambient | 35 | °C/W |
| Drain-Source Avalanche Ratings | | | |
| E _{AS} ⁽⁴⁾ | Avalanche Energy, Single Pulsed | 42 | mJ |

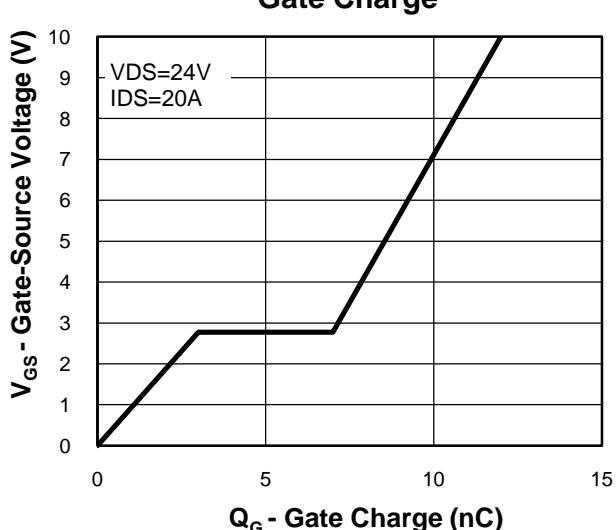
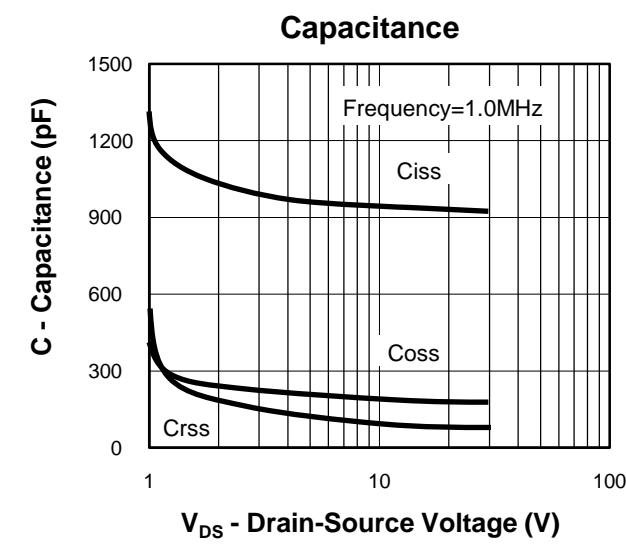
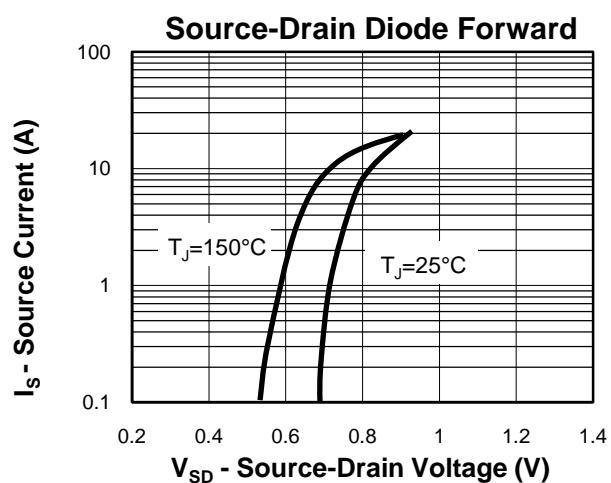
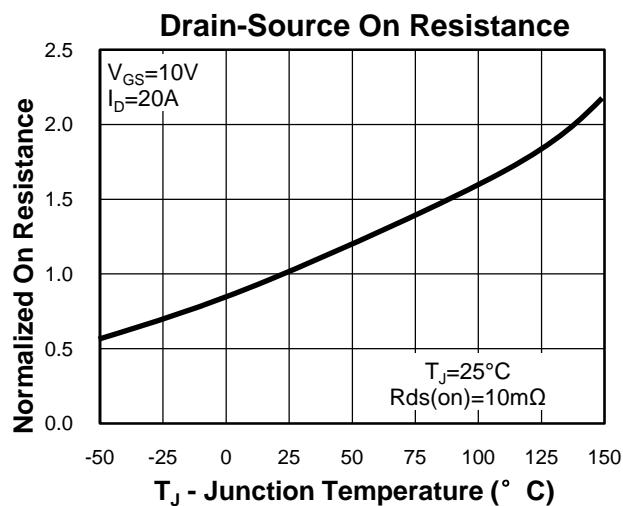
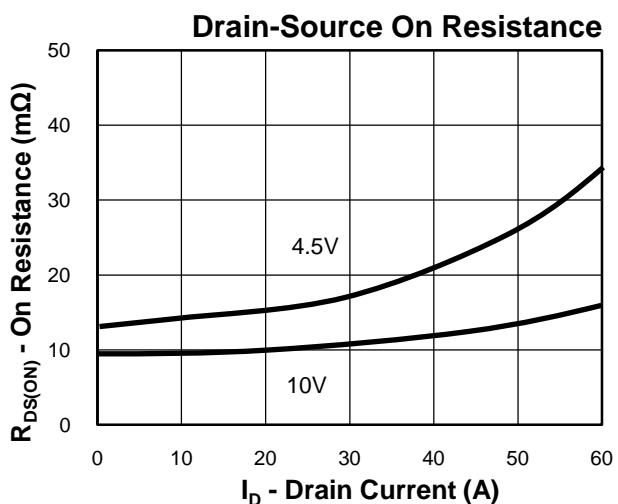
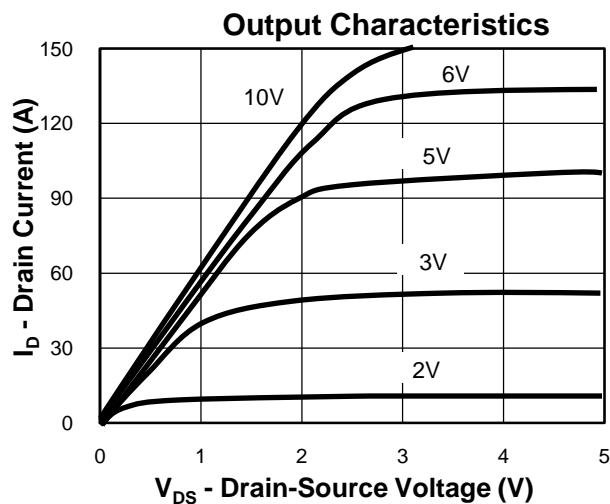
Electrical Characteristics (T_C=25°C Unless Otherwise Noted)

| Symbol | Parameter | Test Condition | Min. | Typ. | Max. | Unit |
|---|----------------------------------|--|------|------|------|------|
| Static Characteristics | | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | V _{GS} =0V, I _{DS} =250μA | 30 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} =30V, V _{GS} =0V | | | 1 | μA |
| | | T _J =125°C | | | 30 | |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} =V _{GS} , I _{DS} =250μA | 1.2 | 1.5 | 2.2 | V |
| I _{GSS} | Gate Leakage Current | V _{GS} =±20V, V _{DS} =0V | | | ±100 | nA |
| R _{DS(ON)} ⁽⁵⁾ | Drain-Source On-state Resistance | V _{GS} =10V, I _{DS} =20A | | 10 | 14 | mΩ |
| | | V _{GS} =4.5V, I _{DS} =16A | | 15 | 23 | mΩ |
| Diode Characteristics | | | | | | |
| V _{SD} ⁽⁵⁾ | Diode Forward Voltage | I _{SD} =20A, V _{GS} =0V | | | 1.2 | V |
| t _{rr} | Reverse Recovery Time | I _{SD} =20A, dI _{SD} /dt=100A/μs | | 15 | | ns |
| Q _{rr} | Reverse Recovery Charge | | | 8 | | nC |
| Dynamic Characteristics ⁽⁶⁾ | | | | | | |
| R _G | Gate Resistance | V _{GS} =0V, V _{DS} =0V, F=1MHz | | 1 | | Ω |
| C _{iss} | Input Capacitance | V _{GS} =0V, V _{DS} =15V, Frequency=1.0MHz | | 938 | | pF |
| C _{oss} | Output Capacitance | | | 142 | | |
| C _{rss} | Reverse Transfer Capacitance | | | 99 | | |
| t _{d(ON)} | Turn-on Delay Time | V _{DD} =15V, R _L =0.75Ω, I _{DS} =20A, V _{GEN} =10V, R _G =3Ω | | 5 | | ns |
| t _r | Turn-on Rise Time | | | 12 | | |
| t _{d(OFF)} | Turn-off Delay Time | | | 19 | | |
| t _f | Turn-off Fall Time | | | 6 | | |
| Gate Charge Characteristics ⁽⁶⁾ | | | | | | |
| Q _g | Total Gate Charge | V _{DS} =24V, V _{GS} =10V, I _{DS} =20A | | 17.5 | | nC |
| Q _{gs} | Gate-Source Charge | | | 3 | | |
| Q _{gd} | Gate-Drain Charge | | | 4.1 | | |

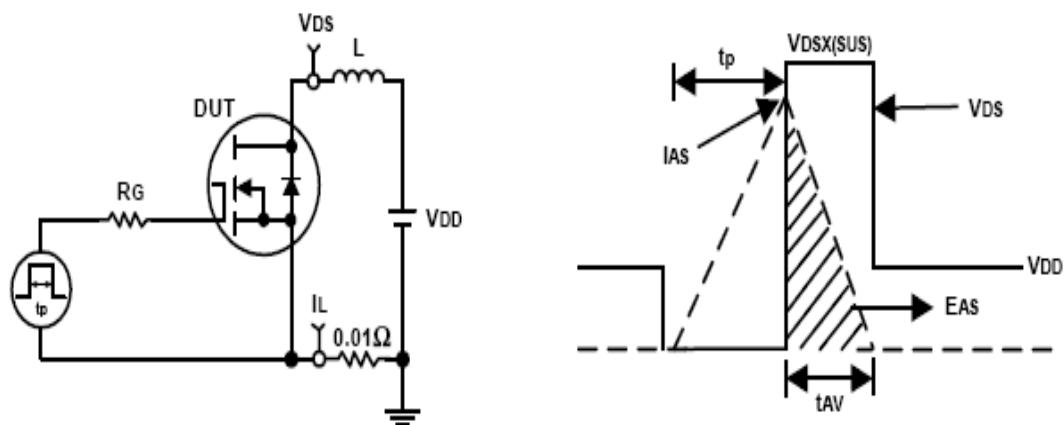
Typical Characteristics



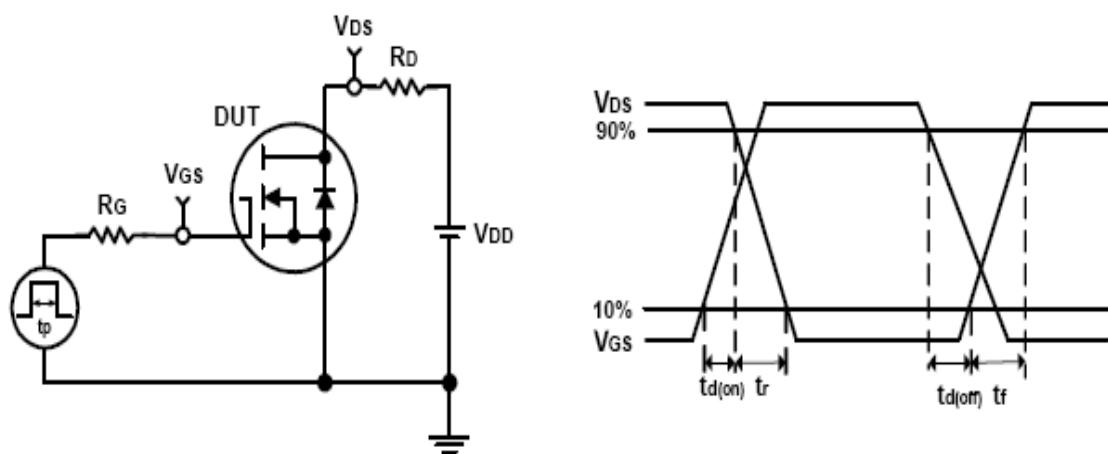
Typical Characteristics



Avalanche Test Circuit and Waveforms



Switching Time Test Circuit and Waveforms



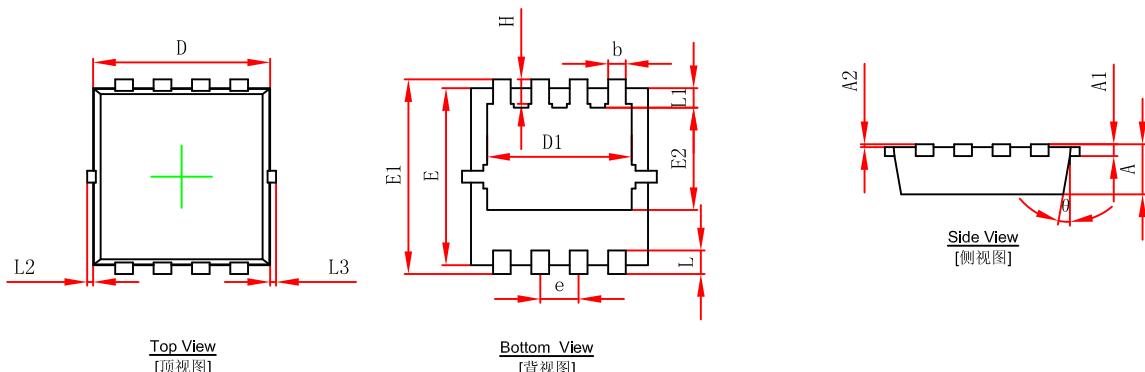


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PDFN 3x3 Plastic-Encapsulate MOSFETS

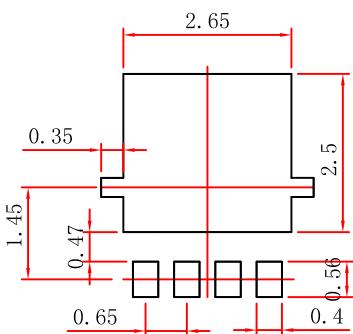
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PDFNWB3.3x3.3-8L Package Outline Dimensions



| Symbol | Dimensions In Millimeters | | Dimensions In Inches | |
|--------|---------------------------|-------|----------------------|-------|
| | Min. | Max. | Min. | Max. |
| A | 0.650 | 0.850 | 0.026 | 0.033 |
| A1 | 0.152 REF. | | 0.006 REF. | |
| A2 | 0~0.05 | | 0~0.002 | |
| D | 2.900 | 3.100 | 0.114 | 0.122 |
| D1 | 2.300 | 2.600 | 0.091 | 0.102 |
| E | 2.900 | 3.100 | 0.114 | 0.122 |
| E1 | 3.150 | 3.450 | 0.124 | 0.136 |
| E2 | 1.535 | 1.935 | 0.060 | 0.076 |
| b | 0.200 | 0.400 | 0.008 | 0.016 |
| e | 0.550 | 0.750 | 0.022 | 0.030 |
| L | 0.300 | 0.500 | 0.012 | 0.020 |
| L1 | 0.180 | 0.480 | 0.007 | 0.019 |
| L2 | 0~0.100 | | 0~0.004 | |
| L3 | 0~0.100 | | 0~0.004 | |
| H | 0.315 | 0.515 | 0.012 | 0.020 |
| θ | 9° | 13° | 9° | 13° |

PDFNWB3.3x3.3-8L Suggested Pad Layout



Note:

1. Controlling dimension: in millimeters.
2. General tolerance: $\pm 0.05\text{mm}$.
3. The pad layout is for reference purposes only.